

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/064,251	LI ET AL.	
Examiner	Art Unit	
HABTE MERED	2416	

	SEARCHED			
Class	Subclass	Date	Examiner	
370	221-223	3/15/2009	НМ	
370	216-218	3/15/2009	НМ	
370	225,227	3/15/2009	НМ	
370	228	3/15/2009	НМ	
370	241,242	3/15/2009	НМ	
370	244	3/15/2009	НМ	
370	250,400	3/15/2009	НМ	
370	401,406	3/15/2009	НМ	
714	712	3/15/2009	НМ	
709	239	3/15/2009	НМ	
379	221.1	3/15/2009	НМ	
379	221.04	3/15/2009	НМ	
398	1-8	3/15/2009	НМ	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched East DB:USPAT, UPGPUB, JPO, EPO	3/15/2009	НМ		
IEEE	3/15/2009	НМ		
Palm Inventor's DB	3/15/2009	НМ		
Consulted John Pezzlo (Primary) on search strategy and rejection strategy	8/24/2007	НМ		
Consulted Doris (SPE) To on srejection strategy	8/28/2007	НМ		
Consulted A. Moe (SPE) on allowable subject matter and rejection strategies	10/10/2008	НМ		
Consulted A. Moe (SPE) on rejection strategy and allowable subject matter	3/12/2009	НМ		